Docket No. 245557US0SX

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Masanobu OGINO, et al.

SERIAL NO: New Application GAU:

FILED: Herewith EXAMINER:

FOR: SEMICONDUCTOR SUBSTRATE AND METHOD OF MANUFACTURE THEREOF

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- □ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number <u>15-0030</u>. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

Norman F. Oblon

Registration No. 24,618

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Fax. (703) 413-2220 (OSMMN 05/03) DOCKET NO.: 245557US0SX page <u>1</u> of <u>1</u>

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THEREOF

STATEMENT OF RELEVANCY

Reference AO (59-35421) of Form PTO-1449:

This document is disclosed in the body of a specification.

Form PTO 1449	U.S. DEPARTMENT OF COMMERCE			ATTY DOCKET NO.		SERIAL NO.		
(Modified)		PATENT AND TRAC	DEMARK OFFICE	245557US0SX		New Application		
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LIST OF RE	FER	ENCES CITED BY AP	PLICANT	Masanobu OGINO, et al.				
				FILING DATE		GROUP		
				Herewith				
U.S. PATENT DOCUMENTS								
EXAMINER		DOCUMENT	DATE	NAME	CLASS	SUB	FILING DATE	
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FOREIGN PATENT DOCUMENTS								
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P	AO	59-35421	02/27/84	Japan			X	
1	AP	58-180018	10/21/83	Japan (with English abstract)			X	
F	AQ	5-315345	11/26/93	Japan (with English abstract)			X	
	AR	6-61477	03/04/94	Japan (with English abstract)			X	
	AS	9-232326	09/05/97	Japan (with English abstract)			X	
	AT	2000-82678	03/21/00	Japan (with English abstract)			X	
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
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